# 1. General Requirements

All components have to be mounted according to the drawing: GBA26800MX The bare board is specified as: GBA610ADB

# 2. Revision History

Version	Date	Revised by	Description				
1.0	2010-APR-13	A. Tutat	Initial Version				
1.1	2010-MAY-28	A. Tutat	some limits adapted				
1.2	2010-DEC-28	A. Tutat	test cases PTC not required				
1.3	2011-JAN-06	A. Tutat	SMPS load resistors (2k)				
1.4	2013-JAN-18	2013-JAN-18 A. Tutat version MX3, MX4 inserted					

### 3. Code Requirements

The board has been laid out according to the requirements in EN81, VDE110-1 (Transient Voltage 4kV; Inhomogeneous Field, Pollution Degree 2 and Safety relevant areas to other areas: Pollution Degree 3; Clearance Distance: Table2; Creepage Distance: Table

Date	Changes	Name	Test Deminerant for		GBA2680	OMY TD
2010-MAY-28	some limits adapted, CA47A-000528	A. Tutat	Test Requirement for PBX BIDI		GDAZ000	JUIVIA_I K
2010-DEC-28	test cases PTC not required, CA47A-000528	A. Tutat	I BX_BIDI	•	12 SHEETS	- SHEET 1
2011-JAN-06	SMPS load resistors (2k), CA47A-000528	A. Tutat	OTIS	RESP	2010-APR-13	A. Tutat
2013-JAN-18	version MX3, MX4 inserted, CN376610	A. Tutat	Elevator Company	CHK	2010-APR-13	M. Dehmlow
			Enigneering Center Berlin	AUT	2010-APR-13	CA47A-000528

### 4. Data logging Requirements for the purpose of statistical analysis.

All measurement results should be written together with the PCB serial number and production-date into a file.

The time-interval to produce a back-up of the file should be determined by the factory. Also must be determined how many records are captured per file.

#### Construction of the file:

- 1. PCB serial number
- 2. production-date
- 3. all measurement results, The variable-names should consist of a combination of Symbol-Name and Parameter-Name.) Visual separation through special character, for example: \*.

#### 5. Electrical Requirements

Unless otherwise noted MIN/MAX values are valid for temperatures between +0degC and +70degC. All typical values are calculated for an ambient temperature of Ta=25degC.

DC values have to be measured with an average reading meter. AC values have to be measured with a true-RMS meter. DC values are marked with the unit V or A, AC values are marked with Vrms or Arms.

The remark "Logic Level" (LL) relates to HCMOS standard: "High" = 3.5V ... 5.7V and "Low"=-0.7V ... 1.0V.

Date	Changes	Name	Took Dominoment for		GBA26800MX TR
2010-MAY-28	some limits adapted, CA47A-000528	A. Tutat	Test Requirement for PBX BIDI		GBA2000UWIA_IR
2010-DEC-28	test cases PTC not required, CA47A-000528	A. Tutat	I BA_BIBI	,	12 SHEETS - SHEET 2
2011-JAN-06	SMPS load resistors (2k), CA47A-000528	A. Tutat	OTIS	RESP	2010-APR-13 A. Tutat
2013-JAN-18	version MX3, MX4 inserted, CN376610	A. Tutat	Elevator Company	CHK	2010-APR-13 M. Dehmlow
			Enigneering Center Berlin	AUT	2010-APR-13 CA47A-000528

### 5.1. Power supply

If within the test cases no other supply voltages are indicated, the board has to be supplied with the following voltages:

24V HL2 +24V / current limitable to max. 500mA at P5.46 (referenced to HL2)

HL2 at P5.44

24V\_SE +24V / current limitable to max. 500mA at P1.1 (referenced to 24V\_SE\_RTN)

24V\_SE\_RTN at P1.2

24V\_SW +24V / current limitable to max. 500mA at P4.1 (referenced to 24V\_SW\_RTN)

24V\_SW\_RTN at P4.2

24V\_SENSE +24V / current limitable to max. 500mA at P5.50 (referenced to 24V\_SENSE\_RTN)

24V\_SENSE\_RTN at P5.48

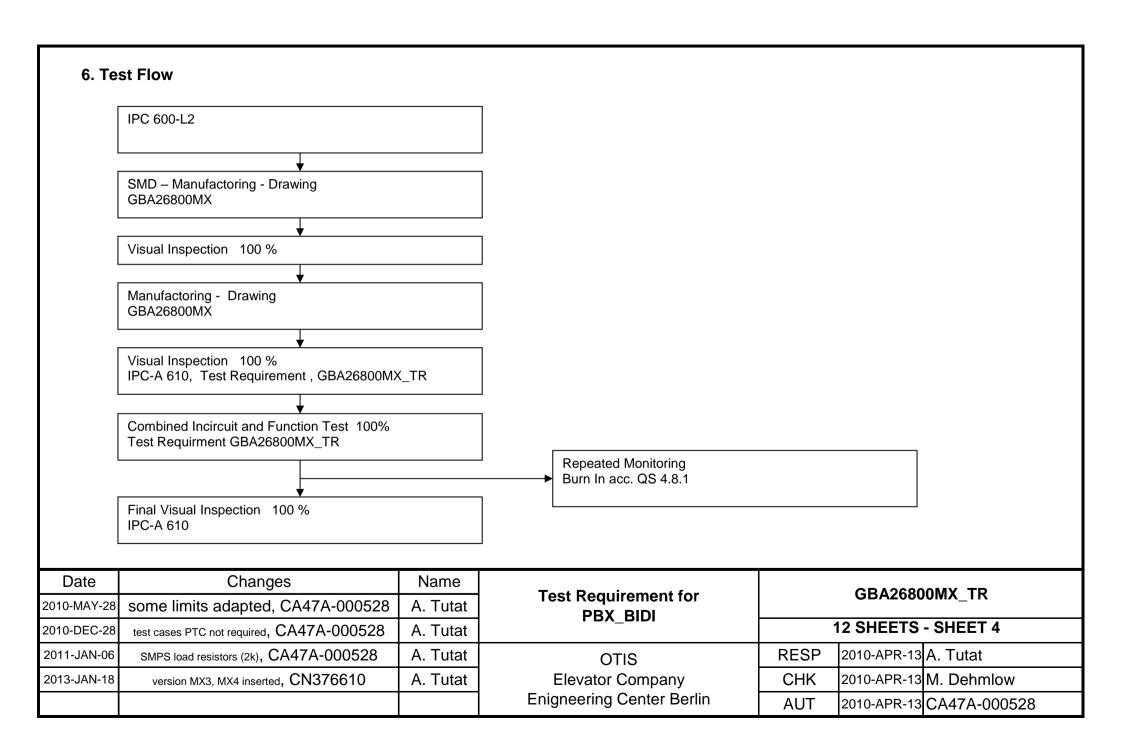
V+15V +15V / current limitable to max. 200mA at P3.40 (referenced to AGND)
V-15V -15V / current limitable to max. 200mA at P3.39 (referenced to AGND)

AGND at P3.38

VCC +5V / current limitable to max. 200mA at P3.13 (referenced to GND)

GND at P3.12

Date	Changes	Name	Took Dominomont for		GBA2680	OMV TD
2010-MAY-28	some limits adapted, CA47A-000528	A. Tutat	Test Requirement for PBX BIDI		GBAZ000	OWIX_TR
2010-DEC-28	test cases PTC not required, CA47A-000528	A. Tutat	I DX_BIDI	•	12 SHEETS	- SHEET 3
2011-JAN-06	SMPS load resistors (2k), CA47A-000528	A. Tutat	OTIS	RESP	2010-APR-13	A. Tutat
2013-JAN-18	version MX3, MX4 inserted, CN376610	A. Tutat	Elevator Company	CHK	2010-APR-13	M. Dehmlow
			Enigneering Center Berlin	AUT	2010-APR-13	CA47A-000528



Test Requirement for PBX_BIDI GBA268	300MX											
All measuring instruments must be calibrated!!!												
2. As an additional document, the circuit diagram of the PCBA												
3. All measuring points : reference points are described in kin											Value range	
4. PBX_BIDI alternatively assembled with CONVERTER- or I												
test cases <b>only</b> for PBX_BIDI, <b>INVERTER</b> -FUNCTIONA test cases <b>only</b> for PBX_BIDI, <b>CONVERTER</b> -FUNCTION						Sar	mples			Low	er Specification Lir	mit
test cases only for BA_DIDI, CONVERTER-FORCHOIT test cases not required for GBA26800MX1, MX2, MX3											er Specification Lir	
Highly Accelerated Life Test, test cases required for HALT												
	Test o	cases			Boa	ard Se	rial Nu	ımbeı	r	LSL	Typical	USL
Description	note	measuring point : reference point	unit									
		@ specified condition	unit									
Power Supply: IGBT Gate Driver PHASE R(U)		iescent current consumption: 24V_SW @ 24VDC								180,00	236,00	290,00
		rrent: IGBT driver SMPS	mA				4			100.00	25225	
SMPS characteristic		iescent current consumption: 24V_SE @ 24VDC								180,00	236,00	360,00
Switched Mode Power Supply		rrent: IGBT driver SMPS, SENSING SMPS VM_VCC_RU: 24V_DRIVER_RTN		-		-	-	$\vdash$		 10,00	11,00	13,00
Davies Sail Detection		SENSE_RU: 24V_DRIVER_RTN	V			-	+			0,10	0,60	0,90
Power Fail Detection		VITCHING ON-DUTY-CYCLE w/o any additional load		<del>                                     </del>	$\dashv$	+	+	$\vdash$	$\dashv$	 5,00	20,00	30,00
		VM CONTROLLER output pin or MOSFET DRAIN								0,00	20,00	30,00
preparation:		ATE_SENSE_RU : 24_DRIVER_RTN	%									
Please add additional load resistors (2k) to:		RAIN_RU : 24_DRIVER_RTN										
1.)	SV	VITCHING FREQUENCY				+	1			140,00	160,00	180,00
, +27V_RU_P : +27V_RU_P_RTN		VM CONTROLLER output pin or MOSFET DRAIN								2,22		,
2.)		ATE_SENSE_RU : 24_DRIVER_RTN	kHz									
+27V_RU_N : +27V_RU_N_RTN	DF	RAIN_RU: 24_DRIVER_RTN										
	0 10	7// DII D 07// DII D DTN				-	+		-	20.00	07.00	20.00
		7V_RU_P : +27V_RU_P_RTN 7V_RU_N : +27V_RU_N_RTN				_	+			26,00 26,00	27,00 27,00	29,00 29,00
		7V_RU_N			-	+	+		-	6,50	7,00	7,50
		F 2V5 RU P:+27V_RU_P_RTN					+			2,38	2,50	2,63
		GBT threshold voltage								2,00	2,40	3,10
		crease <b>+27V_RU_P</b> from 0V until output a transition occurs: HIGH to LO	N							_,00	_,	3, 13
		(1: PF_IGBT_INV : GND										
	M)	(2: PF_IGBT_CONV : GND										
		eparation:										
		connect primary 24V_SW and 24V_SE supply,										
		d an adjustable supply only on										
	+2	7V_RU_P referenced to +27V_RU_P_RTN										
			V									
		F_3V9_RU_N : +27V_RU_N_RTN								6,50	7,00	7,50
		F_2V5_RU_N: +27V_RU_N_RTN								2,38	2,50	2,63
		_IGBT threshold voltage							T	2,00	2,40	3,10
		rease +27V_RU_N from 0V until output a transition occurs: HIGH to LO	N									
		(1: PF_IGBT_INV : GND										
		(2: PF_IGBT_CONV : GND										
	l lar	eparation:										
		connect primary 24V_SW and 24V_SE supply,										
		d an adjustable supply only on										
		7V_RU_N referenced to +27V_RU_N_RTN										

Test Requirement for PBX_BIDI GBA26	SUUMA											
1. All measuring instruments must be calibrated!!! 2. As an additional document, the circuit diagram of the PCB 3. All measuring points: reference points are described in kin 4. PBX_BIDI alternatively assembled with CONVERTER- or test cases only for PBX_BIDI, INVERTER-FUNCTIONATEST CASES only for PBX_BIDI, CONVERTER-FUNCTIONATEST CASES not required for GBA26800MX1, MX2, MX3. 5. Highly Accelerated Life Test, test cases required for HALTEST CASES TEST CASES T	A is required.  INVERTER-FUNCTIONALI  ALITY, GBA26800 <b>MX1, N</b> DNALITY, GBA26800 <b>MX2, N</b> MX4, marked with note: 4	TY  X3, marked with note: 1				Sa	mples				Value range ver Specification Line oer Specification Line	
	Test cases				Bos	ard Se	erial N	ımhe	r	LSL	Typical	USL
Description	note	measuring point : reference point @ specified condition	unit								Тургосі	002
Power Supply: IGBT Gate Driver PHASE S(V)		CC_SV: 24V_DRIVER_RTN : SV: 24V DRIVER RTN	V							10,00	11,00 0,60	13,0 0,9
SMPS characteristic Switched Mode Power Supply Power Fail Detection	SWITCH PWM CC GATE_S	ING ON-DUTY-CYCLE w/o any additional load ONTROLLER output pin or MOSFET DRAIN ENSE_SV: 24_DRIVER_RTN SV: 24_DRIVER_RTN	%							5,00	,	30,0
preparation: Please add additional load resistors (2k) to:	SWITCH PWM CC GATE_S	ING FREQUENCY ONTROLLER output pin or MOSFET DRAIN ENSE_RU: 24_DRIVER_RTN RU: 24_DRIVER_RTN	kHz							140,00	160,00	180,0
1.)		/_P:+27V_SV_P_RTN /_N:+27V_SV_N_RTN								26,00 26,00	27,00 27,00	29,0 29,0
+27V_SV_P : +27V_SV_P_RTN 2.)					+				_	6,50		7,5
-:, +27V_SV_N : +27V_SV_N_RTN		5_SV_P : +27V_SV_P_RTN								2,38	2,50	2,6
-21 V_OV_IV .	Increase MX1: PF MX2: PF  preparat disconne add an a +27V_S\	ct primary 24V_SW and 24V_SE supply, djustable supply only on /_P referenced to +27V_SV_P_RTN	V							2,00		3, 1
		9_SV_N: +27V_SV_N_RTN			_	_				6,50		7,5
		5_SV_N: +27V_SV_N_RTN					_			 2,38	·	2,6
	Increase MX1: PF MX2: PF  preparat disconne add an a	threshold voltage +27V_SV_N from 0V until output a transition occurs: HIGH to LOV _IGBT_INV: GND _IGBT_CONV: GND  ion: ct primary 24V_SW and 24V_SE supply, djustable supply only on /_N referenced to +27V_SV_N_RTN	1							2,00	2,40	3, 1

Test Requirement for PBX_BIDI GBA26800M											
1. All measuring instruments must be calibrated!!! 2. As an additional document, the circuit diagram of the PCBA is required. 3. All measuring points: reference points are described in kind of net 4. PBX_BIDI alternatively assembled with CONVERTER- or INVERT test cases only for PBX_BIDI, INVERTER-FUNCTIONALITY, test cases only for PBX_BIDI, CONVERTER-FUNCTIONALITY test cases not required for GBA26800MX1, MX2, MX3, MX4, 5. Highly Accelerated Life Test, test cases required for HALT, market	CTIONALITY  800MX1, MX3, marked with note: 1  800MX2, MX4, marked with note: 2  with note: 4				Sar	nples			Low	Value range er Specification Lir er Specification Lir	
				<u> </u>		NI					1101
Description	measuring point : reference point @ specified condition	ınit		Воа	ird Sei	rial Nu	umber		LSL	Typical	USL
Power Supply: IGBT Gate Driver PHASE T(W)	PWM_VCC_TW: 24V_DRIVER_RTN	\/							10,00	11,00	13,00
	I_SENSE_TW: 24V_DRIVER_RTN	٧							0,10	0,60	0,90
SMPS characteristic Switched Mode Power Supply Power Fail Detection	SWITCHING ON-DUTY-CYCLE w/o any additional load PWM CONTROLLER output pin or MOSFET DRAIN GATE_SENSE_TW: 24_DRIVER_RTN DRAIN_TW: 24_DRIVER_RTN	%							5,00	20,00	30,00
preparation: Please add additional load resistors (2k) to:	SWITCHING FREQUENCY PWM CONTROLLER output pin or MOSFET DRAIN GATE_SENSE_TW: 24_DRIVER_RTN DRAIN_TW: 24_DRIVER_RTN	:Hz							140,00	160,00	180,00
1.)	+27V_TW_P : +27V_TW_P_RTN								26,00	27,00	29,00
+27V_TW_P : +27V_TW_P_RTN	+27V_TW_N : +27V_TW_N_RTN								26,00	27,00	29,00
2.)	REF_3V9_TW_P: +27V_TW_P_RTN	L							6,50	7,00	7,50
+27V_TW_N : +27V_TW_N_RTN		v							2,38 2,00	2,50	2,63 3,10
	REF_3V9_TW_N: +27V_TW_N_RTN								6,50	7,00	7,50
	REF_2V5_TW_N : +27V_TW_N_RTN	L					$\vdash$	+	2,38	2,50	2,63
	PF_IGBT threshold voltage Increase +27V_TW_N from 0V until output a transition occurs: HIGH to LOW MX1: PF_IGBT_INV: GND MX2: PF_IGBT_CONV: GND  preparation: disconnect primary 24V_SW and 24V_SE supply, add an adjustable supply only on +27V_RU_N referenced to +27V_RU_N_RTN								2,00	2,40	3,10

Test Requirement for PBX_BIDI GBA26800MX													
<ol> <li>All measuring instruments must be calibrated!!!</li> <li>As an additional document, the circuit diagram of the PCBA is required.</li> <li>All measuring points: reference points are described in kind of netnative and the period of the PBX_BIDI alternatively assembled with CONVERTER- or INVERTER test cases only for PBX_BIDI, INVERTER-FUNCTIONALITY, test cases only for PBX_BIDI, CONVERTER-FUNCTIONALITY, test cases not required for GBA26800MX1, MX2, MX3, MX4, mast.</li> <li>Highly Accelerated Life Test, test cases required for HALT, marked</li> </ol>	mes, to R-FUN BBA268 BBA268 arked w	CTIONALITY  800MX1, MX3, marked with note: 1  800MX2, MX4, marked with note: 2  with note: 4				S	Samples	i e			Lowe	Value range er Specification Liner Specification Liner	
		st cases			Во	ard S	Serial N	umbe	er		LSL	Typical	USL
Description	note	measuring point : reference point @ specified condition	unit										
Power Supply: SENSING	1	quiescent current consumption: 24V_SENSE @ 24VDC current: SENSING SMPS	mA								20,00	100,00	200,00
SMPS characteristic Switched Mode Power Supply		VCC_PWM_CONTROLLER : 24V_SMPS_SENSE_RTN	V								10,00	12,00	14,00
Switched Mode Fower Supply		I_SENSE_PWM_CONTROLLER: 24V_SMPS_SENSE_RTN	·								0,10	0,60	0,90
	1	SWITCHING ON-DUTY-CYCLE PWM CONTROLLER output pin or MOSFET DRAIN SMPS_SENSE_GATE: 24V_SMPS_SENSE_RTN SMPS_SENSE_DRAIN: 24V_SMPS_SENSE_RTN	%								22,00	27,00	32,00
	2	SWITCHING ON-DUTY-CYCLE PWM CONTROLLER output pin or MOSFET DRAIN SMPS_SENSE_GATE: 24V_SMPS_SENSE_RTN SMPS_SENSE_DRAIN: 24V_SMPS_SENSE_RTN	%								22,00	39,00	44,00
		SWITCHING FREQUENCY PWM CONTROLLER output pin or MOSFET DRAIN SMPS_SENSE_GATE: 24V_SMPS_SENSE_RTN SMPS_SENSE_DRAIN: 24V_SMPS_SENSE_RTN	kHz								140,00	160,00	180,00
	3	InvTempUref (Addr.: 0x10) CnvTempUref (Addr.: 0x10) measuring point: S+15V / SGND signal: +15V_SENSE / GND_SENSE	mV								14250,00	15000,00	15750,00
	3	-15V_SENSE : GND_SENSE									-15750,00	-15000,00	<del>-14</del> 250,00
Power Supply: PTC Temperature Measurement	4	quiescent current consumption: 24V_HL2 @ 24VDC current: SENSING SMPS	mA								4,00	100,00	200,00
SMPS characteristic Switched Mode Power Supply		SW_TEMP_SENSOR : HL2	kHz						+ +		180,00	200,00	220,00
	3	5V_HL2 : HL2 PTC_ADC: HL2 @ open PTC_1/PTC_6									4,75 3,00	5,00 3,70	5,25 5,00
<b>preparation:</b> Please connect, the test cases referred resistors between the inputs:		PTC_ADC: HL2 @ 1k, 1% resistor between PTC_1/PTC_6	٧								1,00	1,20	1,80
PTC_1 and PTC_6		PTC_ADC: HL2 @ SHORT-CIRCUIT PTC_1/PTC_6 PTC_1: PTC_6	mA						$\vdash$		0,00 4,00	0,32 4,60	0,50 5,60
DC-Link-LED		Pilot LED flashing Frequency									5,00	7,00	15,00
acquisition via a LED sensor												,	-,
preparation:			Hz										
5VDC supply: DCP LED referenced to DCN LED 6 (NE555 Timer-pin1)													
201_225 Totololious to 2011_225_0 (12000 Times pint)													
IGBT Gate Driver voltages		RUP_G11:RUP_E11@PWM_RP, PWM_UP=HIGH:GND									-16,00	-9,50	-5,00
preparation:		RUP_G11:RUP_E11@PWM_RP, PWM_UP= <b>LOW</b> :GND		$\vdash$			+	-	+		14,00	15,70	17,00
1.) All drivers must be stimulated such that a connected IGBT would be		RUN_G21:RUN_E21@PWM_RN, PWM_UN=HIGH:GND		$\vdash$	$\dashv$	+	+	+	+-+		-16,00	-9,50	-5,00
switched on. Add an IGBT Gate-Emitter load, a <b>100nF±10%</b> ceramic or metal foil		RUN_G21:RUN_E21@PWM_RN, PWM_UN= <b>LOW</b> :GND		$\vdash \vdash$	$\dashv$	+	+	+	+		14,00	15,70	17,00
capacitor must be connected between the measuring points:  IGBT Gate to IGBT Emitter		SVP_G11:SVP_E11@PWM_SP, PWM_VP=HIGH:GND							+ +		-16,00	-9,50	-5,00
RUP_G11 : RUP_E11, RUN_G21 : RUN_E21		SVP_G11:SVP_E11@PWM_SP, PWM_VP= <b>LOW</b> :GND					+		† †		14,00	15,70	17,00
SVP_G11 : SVP_E11, SVN_G21 : SVN_E21 TWP_G11 : TWP_E11, TWN_G21 : TWN_E21		SVN_G21:SVN_E21@PWM_SN, PWM_VN=HIGH:GND	<b>1</b> '		$\neg +$			<u> </u>		$\neg$	-16,00	-9,50	-5,00
short circuit: IGBT Collector to IGBT Emitter		SVN_G21:SVN_E21@PWM_SN, PWM_VN= <b>LOW</b> :GND					$\top$				14,00	15,70	17,00
RUP_C1 : RUP_E11 : RUN_E21 SVP_C1 : SVP_E11 : SVN_E21		TWP_G11:TWP_E11@PWM_TP, PWM_WP=HIGH:GND									-16,00	-9,50	-5,00
TWP_C1 : TWP_E11 : TWN_E21		TWP_G11:TWP_E11@PWM_TP, PWM_WP= <b>LOW</b> :GND									14,00	15,70	17,00
2.) only GBA26800MX2		TWN_G21:TWN_E21@PWM_TN, PWM_WN=HIGH:GND									-16,00	-9,50	-5,00
OUT_EN_CONV:GND set to HIGH level		TWN_G21:TWN_E21@PWM_TN, PWM_WN= <b>LOW</b> :GND									14,00	15,70	17,00

All measuring instruments must be calibrated!!!													
<ol> <li>As an additional document, the circuit diagram of the PCBA is required.</li> <li>All measuring points: reference points are described in kind of netnamed.</li> <li>PBX_BIDI alternatively assembled with CONVERTER- or INVERTER-test cases only for PBX_BIDI, INVERTER-FUNCTIONALITY, GE test cases only for PBX_BIDI, CONVERTER-FUNCTIONALITY, GE test cases not required for GBA26800MX1, MX2, MX3, MX4, marks.</li> <li>Highly Accelerated Life Test, test cases required for HALT, marked w</li> </ol>	es, test point FUNCTIONA A26800 <b>MX1</b> , BA26800 <b>MX2</b> Ked with note:	LITY , MX3, marked with note: 1 , MX4, marked with note: 2					Samples					Value range er Specification Li er Specification Li	
	Test cas	es			Во	ard	Serial N	umbe	er		LSL	Typical	USL
Description	note	measuring point : reference point @ specified condition	unit										
DRIVER_RESET_N logic low pulse width	GBA26	6800MX1: OCT_INV referenced to GND									200	360	50
Description of the function: HCPL316J FAULT* changes from a high impedance state to a logic ow, if the voltage on the HCPL316J DESAT pin exceeding an internal reference voltage of 7.5V while the IGBT is on. HCPL316J FAULT* output remains low until HCPL316J RESET* s brought low. HCPL316J FAULT* output is an open collector which allows the FAULT* outputs	GBA26	pulse width n only short circuit RUP_C1 : RUP_E11									200	300	
from all HCPL-316Js to be connected together in a "wired OR" forming the signals:  GBA26800MX1: OCT_INV referenced to GND  GBA26800MX2: CNV_OC_FLT referenced to GND  When one of the six HCPL316J FAULT* outputs change to low, the HCPL316J RESET* input will change to low after a time delay of the	GBA26	6800MX1: OCT_INV referenced to GND 6800MX2: CNV_OC_FLT referenced to GND  pulse width n only short circuit RUP_E11 : RUN_E21									200	360	50
PWM_SP=LOW:GND, PWM_VP=LOW:GND PWM_SN=LOW:GND, PWM_VP=LOW:GND PWM_SN=LOW:GND, PWM_VP=LOW:GND PWM_SN=LOW:GND, PWM_VP=LOW:GND PWM_SN=LOW:GND, PWM_VP=LOW:GND PWM_SN=LOW:GND, PWM_VP=LOW:GND	GBA26	6800MX1: OCT_INV referenced to GND 6800MX2: CNV_OC_FLT referenced to GND  pulse width n only short circuit SVP_C1 : SVP_E11									200	360	50
PWM_TN= <b>LOW</b> :GND, PWM_WN= <b>LOW</b> :GND  2.)  Add an IGBT Gate-Emitter load, a 100nF±10% ceramic or metal foil capacitor must be connected between the measure points:  GBT Gate to IGBT Emitter  RUP_G11: RUP_E11, RUN_G21: RUN_E21  SVP_G11: SVP_E11, SVN_G21: SVN_E21	GBA26	6800MX1: OCT_INV referenced to GND 6800MX2: CNV_OC_FLT referenced to GND  pulse width n only short circuit SVP_E11 : SVN_E21	ms								200	360	5
Realize the following possibility to change between: short circuit / open for approximate 1ms: GBT Collector to IGBT Emitter	ODAG										999	000	
RUP_C1: RUP_E11, RUP_E11: RUN_E21 SVP_C1: SVP_E11, SVP_E11: SVN_E21 TWP_C1: TWP_E11, TWP_E11: TWN_E21  4.) only GAA26800MX2 OUT_EN_CONV:GND set to HIGH level	GBA26	6800MX1: OCT_INV referenced to GND 6800MX2: CNV_OC_FLT referenced to GND  pulse width n only short circuit TWP_C1 : TWP_E11									200	360	50
DESAT pins are executed successively by open only one of the short circuit "IGBT Collector to IGBT Emitter" for approximate 60ms.  Keep a wait time condition to the next test case of approximate 500ms.  All tests must be processed 2 times sequentially, n order to guarantee that no latch up effect appears.	GBA26	6800MX1: OCT_INV referenced to GND 6800MX2: CNV_OC_FLT referenced to GND  pulse width n only short circuit TWP_E11 : TWN_E21									200	360	50

Test Requirement for PBX_BIDI GBA26800MX													
1. All measuring instruments must be calibrated!!! 2. As an additional document, the circuit diagram of the PCBA is require 3. All measuring points: reference points are described in kind of netnar 4. PBX_BIDI alternatively assembled with CONVERTER- or INVERTER test cases only for PBX_BIDI, INVERTER-FUNCTIONALITY, Gettest cases only for PBX_BIDI, CONVERTER-FUNCTIONALITY, Gettest cases not required for GBA26800MX1, MX2, MX3, MX4, mas 5. Highly Accelerated Life Test, test cases required for HALT, marked to the convergence of the case of the convergence of the case	mes, t R-FUN BA268 BA26 rked v	CTIONALITY B00MX1, MX3, marked with note: 1 800MX2, MX4, marked with note: 2 with note: 4				Sam	ples					Value range ver Specification Liner Specification Line	
	Te	est cases		E	Board	l Seri	al Nun	ber			LSL	Typical	USL
Description	note	measuring point : reference point @ specified condition	unit										
POWER FAIL MONITORING thresholds PFAIL_RS_CONV signal changes from 1.) statical LOW level 2.) TOGGLE between LOW and HIGH 3.) statical HIGH level	2	PFAIL_RS_CONV / GND threshold toggle Decrease US from 7.4Vpp until PFAIL_RS_CONV threshold changes from statical LOW to TOGGLE									1,00	1,30	4,76
Umax_line_to_line=480V*1.1 resultant max. voltage range: ±3.7V (Vpp=7.4V) Umin_line_to_line=340V resultant min. voltage: Vpp=4.76V		PFAIL_RS_CONV / GND threshold statical LOW Decrease US from 7.4Vpp until PFAIL_RS_CONV threshold changes from TOGGLE to statical HIGH	Vpp								0,30	0,70	1,00
preparation: adjustable sinus voltage supply 7.4Vpp@50Hz, offset=0V to US / GND_SENSE													
Hall Effect Current Sensor LEM: LA200-P TAMURA: S26P200D15Y		SENSE_IR, SENSE_IU : GNDA output-current @ 0A									-1,00	0,00	1,00
VAC: T60404-N4646-X201 <b>current conversion ratio: 1:2000</b> measure the output-current at a given input-current		SENSE_IR, SENSE_IU : GNDA LEM_IR_output-current @ 2A									0,80	1,00	1,20
preparation: Apply R=60ohm between:		SENSE_IR, SENSE_IU : GNDA LEM_IR_output-current @ <b>-2A</b>									-1,20	-1,00	-0,80
SENSE_IR, SENSE_IU and GNDA SENSE_IS, SENSE_IV and GNDA		SENSE_IS, SENSE_IV : GNDA LEM_IS_output-current @ 0A	mA								-1,00	0,00	1,00
Input-current source cable put through the hole once. Polarity markings: A positive measuring output-current is obtained on terminal M (pin 2),		SENSE_IS, SENSE_IV : GNDA LEM_IS_output-current @ 2A									0,80	1,00	1,20
when the primary input-current flows in the direction of the arrow.		SENSE_IS, SENSE_IV : GNDA  LEM_IS_output-current @ <b>-2A</b>									-1,20	-1,00	-0,80
CHG-RELAY contact resistance	2	R_RES:RUO@REL1, REL2: contacts opened										contacts opened	
preparation: OUT_EN_INV:GND set to HIGH level OUT_EN_CONV:GND set to HIGH level		R_RES:RUO@REL1, REL2: contacts closed	YES									contacts closed	
REL1, REL2: contacts closed CHRG_N:GND to LOW		S_RES:SVO@REL1, REL2: contacts opened	or NO									contacts opened	
REL1, REL2: contacts opened CHRG N:GND to HIGH		S_RES:SVO@REL1, REL2: contacts closed							+	+		contacts closed	

Test Requirement for PBX_BIDI GBA26800MX  1. All measuring instruments must be calibrated!!!											
<ol> <li>All measuring instruments must be calibrated!!!</li> <li>As an additional document, the circuit diagram of the PCBA is requi</li> <li>All measuring points: reference points are described in kind of netn</li> <li>PBX_BIDI alternatively assembled with CONVERTER- or INVERTE test cases only for PBX_BIDI, INVERTER-FUNCTIONALITY, test cases only for PBX_BIDI, CONVERTER-FUNCTIONALITY, test cases not required for GBA26800MX1, MX2, MX3, MX4, m</li> <li>Highly Accelerated Life Test, test cases required for HALT, marked</li> </ol>	ames, test points or component designator. R-FUNCTIONALITY GBA26800MX1, MX3, marked with note: 1 GBA26800MX2, MX4, marked with note: 2 arked with note: 4				San	nples				Value range ver Specification Li	
	Test cases			Boa	rd Ser	ial Nu	mber		LSL	Typical	USL
Description	measuring point : reference point @ specified condition	unit									
VRS, VST voltage gain calibration	2   REF_SEC / GNDA (±10%) equation: 5V*-0.4115*0.89111=-1.83356V								-2017,40	-1834,00	-1650,60
and transfer gain K3 (plausibility) check	measuring point: DC_VRS / SGND (±10%) signal: VRS_DC_N / GND_SENSE								1852,20	2058,00	2263,80
	measuring point: VRS / AGND (±25%) signal: VRS_OUT_DC_N / GNDA equation: 2.0576V*0.89111=1.8335V	mV							1375,50	1834,00	2292,50
Linear Optocoupler GAA629CL1	measuring point: VRS_N / AGND signal: VRS_OUT_N / GNDA								-1500,00	0,00	1500,00
Vendor Vishay: IL300-EF-X017T ransfer gain K3 = $0.851 - 1.061 \pm 0.5\%$ Tamb = $0 ^{\circ}$ C to 75 $^{\circ}$ C	transfer gain K3_VRS (plausibility) check proceeding:								0,80	1,00	1,10
Vendor Agilent / Avago: HCNR201 ransfer gain K3 = 0.93 - 1.07	calculate with the following equation:  K3_VRS=VRS_OUT_DC_N / (0.89111*VRS_DC_N)										
	measuring point: DC_VST / SGND (±10%) signal: VST_DC_N / GND_SENSE								1852,20	2058,00	2263,80
	measuring point: VST / AGND (+-25%) signal: VST_OUT_DC_N / GNDA equation: 2.0576V*0.89111=1.8335V	mV							1375,50	1834,00	2292,50
	measuring point: VST_N / AGND signal: VST_OUT_N / GNDA								-1500,00	0,00	1500,00
	transfer gain K3_VST (plausibility) check proceeding:								0,80	1,00	1,10
	calculate with the following equation:  K3_VST= VST_OUT_DC_N / (0.89111*VST_DC_N)										
IGBT TEMPERATURE MEASUREMENT and transfer gain K3 (plausibility) check preparation: measure with connected resistor 5kohm, ±0.1% between NTC1 / NTC2	NTC1:NTC2 (1.86V±10%)  measuring point: TEMP_IGBT / GNDA signal: TEMP_IGBT / GNDA equation: typical: (3.107V*0.89111)-0.7258=2.04V with gain range IL300: 0.81.2 min.: (0.8*2.77V)-0.7258=1.49V (-3% = 1.445V) max.: (1.2*2.77V)-0.7258=2.6V (+3% = 2.68V)								1670,00 1445,00		2050,00 2680,00
	InvTempUn (Addr.: 0x12) CnvTempUn (Addr.: 0x12) measuring point: TEMP_UN / GNDA signal: TEMP_UN / GNDA	mV							1080,00	1200,00	1320,00
	InvTempUin (Addr.: 0x14) CnvTempUin (Addr.: 0x14) preparation: measure with connected resistor 5kohm between NTC1 / NTC2 measuring point: NTC1 / SGND signal: NTC1 / GND_SENSE								2950,00	3110,00	3270,00
	transfer gain K3_TEMP (plausibility) check proceeding: calculate with the following equation: K3_TEMP= (TEMP_IGBT+(TEMP_UN*0.604)) / (NTC1*0.89111)								0,80	1,00	1,10
DC-LINK VOLTAGE MEASUREMENT and transfer gain K3 (plausibility) check	InvUdclUin (Addr.: 0x18) measuring point: DC_ME / GND_SENSE signal: DC_ME / GND_SENSE equation: typical: 1.2V*2.4864=3V								2900,00	3000,00	3100,00
preparation:	InvUdclUout (Addr.: 0x1A) measuring point: UDCL / GNDA signal: UDCL / GNDA equation:	mV							2070,00	2673,00	3220,00
CALIBRATED precision DC voltage reference DUTPUT VOLTAGE: +1.2V ±0.2% max LOW NOISE: 10µVPP max (0.1Hz to 10Hz)  conecetd to DCP_U_ME_1 / GND_SENSE	typical: 3V*0.89111=2,673V with gain range IL300: 0.81.2 min.: 0.8*2,673V=2.138V (-3% = 2.07V) max.: 1.2*2,673V=3.208V										
2.) short circuit is needed between DCN_U_ME_1 / GND_SENSE	transfer gain K3_UDC (plausibility) check proceeding: calculate with the following equation: K3_UDC= UDCL / (0.89111*DC_ME)								0,80	1,00	1,10

As an additional document, the circuit diagram of the PCBA is requi- All measuring points: reference points are described in kind of neth- PBX_BIDI alternatively assembled with CONVERTER- or INVERTE test cases only for PBX_BIDI, INVERTER-FUNCTIONALITY, test cases only for PBX_BIDI, CONVERTER-FUNCTIONALITY, test cases not required for GBA26800MX1, MX2, MX3, MX4, m Highly Accelerated Life Test, test cases required for HALT, marked	ames, test points of ER-FUNCTIONALI GBA26800MX1, Narked with note: 4 d with note: 3	ITY MX3, marked with note: 1 MX4, marked with note: 2 1				Samp				Uţ	Value range ower Specification oper Specification	Limit Limit
Description	Test cases	s measuring point : reference point @ specified condition	unit	Bo	oard	Seria	ıl Nur	mber		LSL	Typical	USL
rdware-dependent mining values  sumed measured values, see table above, cutated on values in [mV] be storing in the PROM / bytes from trimming values must be written into the lower dresses.  A268800MX1, MX3: I2C DEVICE Addr.: # 2 A26800MX2, MX4: I2C DEVICE Addr.: # 4 Bust lines:  A268800MX1, MX3: I2C_SCL0_INV, I2C_DA0_INV A26800MX1, MX3: I2C_SCL0_CONV, I2C_DA0_CONV BA26800MX2, MX4: I2C_SCL0_CONV, I2C_DA0_CONV BA26800MX2, MX4: I2C_SCL0_CONV, I2C_DA0_CONV BA26800MX1, MX3: I2C_SCL0_CONV, I2C_DA0_CONV BA26800MX1, MX1093400021  P/N:G1A26800MX1A-LF  REV:2009-07-22  A26800MX1, MX3: Package code:  A26800MX1, MX3: Package code:  A26800MX1, MX3: voltage_code:  A26800MX1, MX3: voltage_code:  A26800MX1, MX3: Drive version number:  A26800MX1, MX3: Drive version number:  A26800MX1, MX3: Drive version number:  B369-1000.00010F  B37000.00010F  B47000.00010F	CnvTem values m InvTemp CnvTem values m InvTemp CnvTem values m InvTemp CnvTem values m proceed calculat InvTemp CnvTem values m proceed calculat CnvVrst values m proceed calculat CnvVst	the with the following equation: DUOUTE TEMP_IGBT+9060/15000*InvTempUn InpUoUTE TEMP_IGBT+9060/15000*CnvTempUn InpUoUTE TEMP_IGBT+9060/15000*CnvTempUn IUIN (Addr.: 0x18) Inargin: 274330003242  UINDC (Addr.: 0x18) Imargin: 450050005500  Iding: It with the following equation: UINDC=VRS_DC_N*2.43  UOUT (Addr.: 0x1A) Inargin: 187026673412  UOUTDC (Addr.: 0x1A) Inargin: 350044555400  Iding: It with the following equation: UOUTC=VRS_OUT_DC_N*2.43  UOUT (Addr.: 0x1C) Inargin: -150001500 Int: IOUT_N < 0) write (65536 - abs(VRS_OUT_N))  IVRS_OUT_N >= 0) then write CnvVrsUout equal to VRS_OUT_N with the following equation: UINDC (Addr.: 0x1E) Inargin: 450050005500  Iding: It with the following equation: UINDC=VST_DC_N*2.43  UOUTDC (Addr: 0x20) Inargin: 350044555400  Iding: It with the following equation: UINDC=VST_DC_N*2.43  UOUTDC=VST_OUT_DC_N*2.43  UOUTDC=VST_OUT_DC_N*2.43  UOUTDC=VST_OUT_DC_N*2.43  UOUTDC=VST_OUT_DC_N*2.43  UOUTDC=VST_OUT_DC_N*2.43  UOUTDC=VST_OUT_DC_N*2.43  UOUTDC=VST_OUT_DC_N*2.43  UOUTDC=VST_OUT_DC_N*2.43  UOUTC_N < 0) write (65536 - abs(VST_OUT_N))  INTERCATE OUT_N >= 0) then write CnvVstUout equal to VST_OUT_N with convolution of the property of the pro										
### Code; Otis definition; e.g. ### Code; Otis definition; e.g. ### Code; Otis definition; e.g. ### Code;	hardward addr: 0x addr: 0x addr: 0x must be hardward addr: 0x	set to enable the trimming parameter with set 0xDEC0 after end of the test&calibration x1C data: C0 x1D data: DE  nufTestId (addr: 0x24) set to enable the trimming parameter with set 0xDEC0 after end of the test&calibration x24 data: C0 x25 data: DE	HEX									